

Docket No.: 60188-044

*Hj*  
*Cham*  
*2-17*  
**PATENT**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of :

Hirokazu YONEZAWA, et al. :

Serial No.: :

Group Art Unit:

Filed: March 19, 2001 :

Examiner:

For: APPARATUS AND METHOD FOR CALCULATING TEMPORAL DETERIORATION  
MARGIN AMOUNT OF LSI, AND LSI INSPECTION METHOD

1c872 U.S. PTO  
09/810518  
03/19/01

**INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
Washington, DC 20231

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

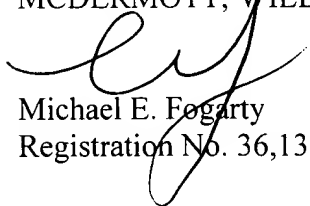
This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

Serial No.:

U.S. Patent No. 5,974,247 is related to Japanese Patent Laid-open Publication No. 10-124565 and U.S. Patent No. 6,047,247 is related to Japanese Patent No. 3046269.

Respectfully submitted,

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# INFORMATION DISCLOSURE CITATION IN AN APPLICATION

(PTO-1449)

 ATTY. DOCKET NO.  
**60188-044**

SERIAL NO.

 APPLICANT  
**Hirokazu YONEZAWA, et al.**

 FILING DATE  
**March 19, 2001**

GROUP

 1c872 U.S. PTO  
09/810516


## U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
	5,533,197	July 2, 1996	MORAN et al.			
	5,634,001	May 27, 1997	MITTL et al.			
	5,974,247	Oct. 26, 1999	YONEZAWA			
	6,047,247	Apr. 4, 2000	IWANISHI et al.			

## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
	10-124565	May 15, 1998	JAPAN				
	3046269	Mar. 17, 2000	JAPAN				

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER	
DATE CONSIDERED	

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.